

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/065,365 BASSETT ET AL.	
		Examiner	Art Unit Cynthia Britt	2133 Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,448,796	09-2002	Ellison et al.	324/754
	B	US-6,658,613	12-2003	Rearick et al.	714/724
	C	US-6,556,938	04-2003	Rohrbaugh et al.	702/117
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	0388790	09-1990	EP	Littlebury	G01R/ 31/28
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NON-PATENT DOCUMENTS

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	U	"A Study of the Optimization of DC Parametric Tests" Chang, J.M. International Test Conference 1990 Proceedings: 10-14 Sept. 1990 pages 478 - 487 Inspec Accession Number: 3976214
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

